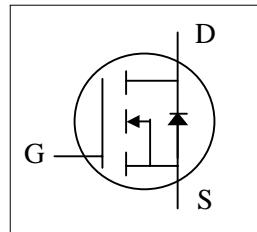
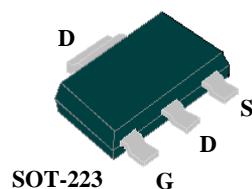




- ▼ Simple Drive Requirement
- ▼ Lower Gate Charge
- ▼ Fast Switching Characteristic
- ▼ Halogen Free & RoHS Compliant Product



$BV_{DSS}$	100V
$R_{DS(ON)}$	160m $\Omega$
$I_D$	2.8A



## Description

Advanced Power MOSFETs from APEC provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The SOT-223 package is designed for surface mount application, larger heatsink than SO-8 and SOT package.

## Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	100	V
$V_{GS}$	Gate-Source Voltage	+20	V
$I_D @ T_A=25^\circ C$	Continuous Drain Current <sup>3</sup> , $V_{GS} @ 10V$	2.8	A
$I_D @ T_A=70^\circ C$	Continuous Drain Current <sup>3</sup> , $V_{GS} @ 10V$	2.2	A
$I_{DM}$	Pulsed Drain Current <sup>1</sup>	10	A
$P_D @ T_A=25^\circ C$	Total Power Dissipation	2.8	W
$T_{STG}$	Storage Temperature Range	-55 to 150	°C
$T_J$	Operating Junction Temperature Range	-55 to 150	°C

## Thermal Data

Symbol	Parameter	Value	Units
$R_{thj-a}$	Maximum Thermal Resistance, Junction-ambient <sup>3</sup>	45	°C/W



### Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	100	-	-	V
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=2\text{A}$	-	-	160	$\text{m}\Omega$
		$V_{\text{GS}}=5\text{V}, I_{\text{D}}=1\text{A}$	-	-	290	$\text{m}\Omega$
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	1	-	3	V
$g_{\text{fs}}$	Forward Transconductance	$V_{\text{DS}}=10\text{V}, I_{\text{D}}=2\text{A}$	-	3.2	-	S
$I_{\text{DSS}}$	Drain-Source Leakage Current	$V_{\text{DS}}=80\text{V}, V_{\text{GS}}=0\text{V}$	-	-	25	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Source Leakage	$V_{\text{GS}}=\pm 20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	$\pm 100$	nA
$Q_{\text{g}}$	Total Gate Charge <sup>2</sup>	$I_{\text{D}}=2\text{A}$	-	6	9.6	nC
$Q_{\text{gs}}$	Gate-Source Charge	$V_{\text{DS}}=50\text{V}$	-	1.5	-	nC
$Q_{\text{gd}}$	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=4.5\text{V}$	-	3.5	-	nC
$t_{\text{d(on)}}$	Turn-on Delay Time <sup>2</sup>	$V_{\text{DS}}=50\text{V}$	-	5	-	ns
$t_{\text{r}}$	Rise Time	$I_{\text{D}}=1\text{A}$	-	6	-	ns
$t_{\text{d(off)}}$	Turn-off Delay Time	$R_{\text{G}}=3.3\Omega$	-	16	-	ns
$t_{\text{f}}$	Fall Time	$V_{\text{GS}}=10\text{V}$	-	6	-	ns
$C_{\text{iss}}$	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	400	640	pF
$C_{\text{oss}}$	Output Capacitance	$V_{\text{DS}}=25\text{V}$	-	55	-	pF
$C_{\text{rss}}$	Reverse Transfer Capacitance	f=1.0MHz	-	35	-	pF

### Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$V_{\text{SD}}$	Forward On Voltage <sup>2</sup>	$I_{\text{S}}=2.1\text{A}, V_{\text{GS}}=0\text{V}$	-	-	1.3	V
$t_{\text{rr}}$	Reverse Recovery Time <sup>2</sup>	$I_{\text{S}}=2\text{A}, V_{\text{GS}}=0\text{V}$	-	35	-	ns
$Q_{\text{rr}}$	Reverse Recovery Charge	$dI/dt=100\text{A}/\mu\text{s}$	-	55	-	nC

### Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse test
- 3.Surface mounted on 1 in<sup>2</sup> copper pad of FR4 board, t  $\leq$  10sec ; 120 °C/W when mounted on Min. copper pad.

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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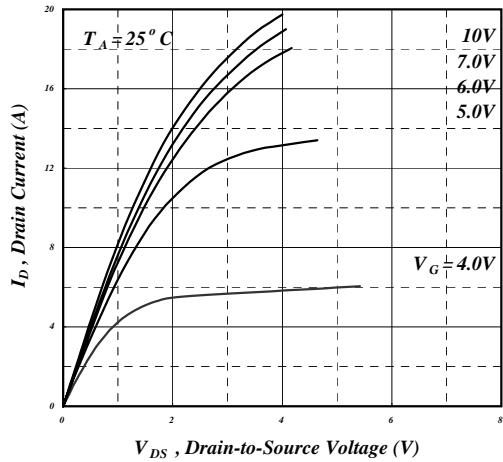


Fig 1. Typical Output Characteristics

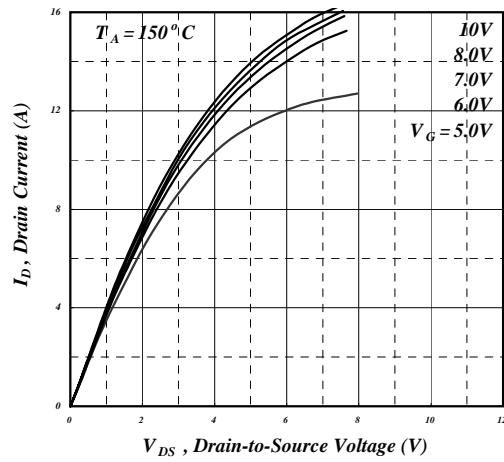


Fig 2. Typical Output Characteristics

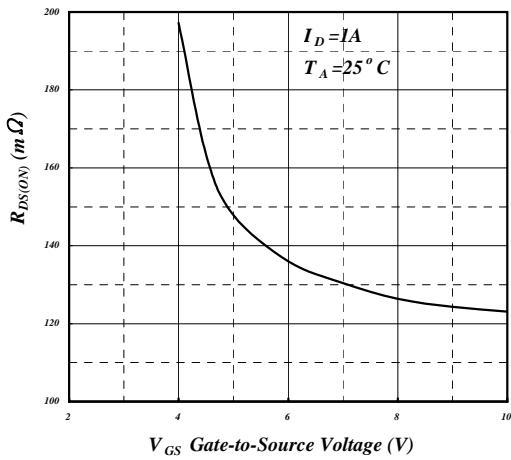


Fig 3. On-Resistance v.s. Gate Voltage

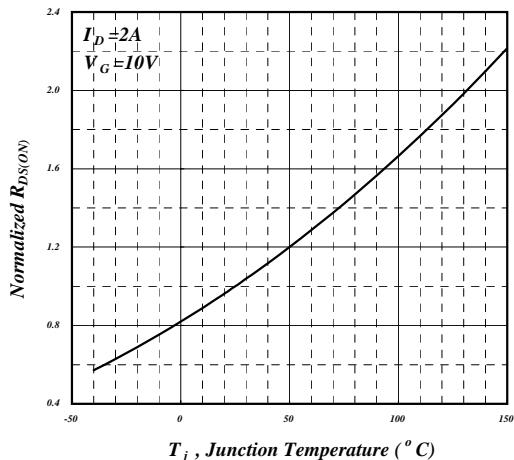


Fig 4. Normalized On-Resistance v.s. Junction Temperature

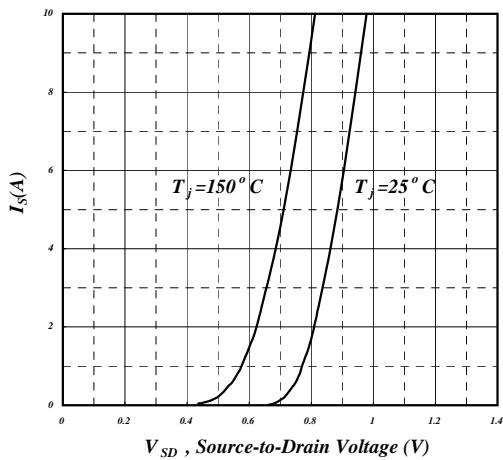


Fig 5. Forward Characteristic of Reverse Diode

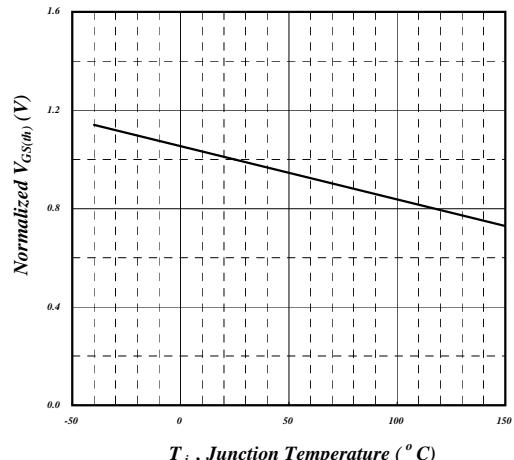


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

